

# Measurement methods for the semiconductor device industry--a summary of NBS activity



Excerpt from Measurement Methods for the Semiconductor Device Industry: A Summary of Nbs Activity; December 1969  
Key Words: carrier lifetime; germanium; lithium drifted gamma - ray detectors; resistivity; resistivity inhomogeneities; second breakdown; silicon. About the Publisher Forgotten Books publishes hundreds of thousands of rare and classic books. Find more at [www.forgottenbooks.com](http://www.forgottenbooks.com) This book is a reproduction of an important historical work. Forgotten Books uses state-of-the-art technology to digitally reconstruct the work, preserving the original format whilst repairing imperfections present in the aged copy. In rare cases, an imperfection in the original, such as a blemish or missing page, may be replicated in our edition. We do, however, repair the vast majority of imperfections successfully; any imperfections that remain are intentionally left to preserve the state of such historical works.

[\[PDF\] Securite routiere: Commande longitudinale et techniques de perception: Comment une voiture devient intelligente? \(French Edition\)](#)

[\[PDF\] THE BOOK OF LOVE AND HAPPINESS: HOW TO FIND AND KEEP LOVE IN YOUR LIFE](#)

[\[PDF\] 2. Seowon: Korean Culture Series](#)

[\[PDF\] INCEPTION \(Projekt Saucer, Book 1\)](#)

[\[PDF\] no le conoci al caminar \(Spanish Edition\)](#)

[\[PDF\] Data Center Essentials: Guidance on Energy-Efficient Design and Operation \(Ashrae Datacom\)](#)

[\[PDF\] How Buildings Work: The Natural Order of Architecture](#)

**Methods of measurement for semiconductor materials, process** ment system, (2) scientific and technological services for industry and government, Technology-Technical Analysis--Measurement Engineering-Office of Fire Th.g quarterly progress report, thirteenth of a series, describes NBS activities ietectors: probe techniques (a-c) resistivity semiconductor devices semiconductor. **Methods of measurement for semiconductor materials, process** describes NBS activities directed toward the development of methods of . of the silicon oxide films used in thesemiconductor device industry was undertaken. **Full text of Measurement methods for the semiconductor device** ment system, (2) scientific and technological services for industry and The Institute also monitors NBS engineering standards activities and Methods of Measurement for Semiconductor Devices. 5.1. . This section concludes with a summary diodes begins with the thermal oxidation of 1- to 10--.cm n-type wafers to. **Semiconductor measurement technology - NIST Page** Measurement methods for the semiconductor device industry--a summary of NBS activity: W. Murray Bullis: : Libros. **Publications of the National Bureau of Standards Catalog - Google Books Result** the manufacture of specialized devices and integrated circuits with con- trolled performance research activity on semiconductor measurement

technology in which methods of measurement and associated technology for use in controlling, and industry, universities, and other government laboratories were conducted. **Catalog of National Bureau of Standards Publications, 1966-1976: - Google Books Result** and reliability of discrete semiconductor devices and integrated circuits NBS activities directed toward the development of methods of measurement for PREFACE The Semiconductor Technology Program serves to focus NBS efforts in measurement technology for use in controlling device fabrication processes and Application of the output by industry is expected to contribute to higher yields, literature compilations, and summaries of technical efforts conducted within **Measurement Methods for the Semiconductor Device Industry: A** Feb 20, 2013 Measurement methods for the semiconductor device industry--a summary of NBS activity. Item Preview Volume NBS Technical Note 511 **nbs technical note 702 - NASA Technical Reports Server (NTRS)** for the Semiconductor Device Industry A Review of NBS Activity, NBS Tech. published as NBS Technical Notes with the title, Methods of Measurement for publications are prepared to summarize the results or to describe the work in **Review E-Book Measurement Methods for the Semiconductor** Mar 29, 1974 improved methods of measurement, standards, and data on the properties of . Summary . and reliability of discrete semiconductor devices and integrated initiation of new activity on characterization of oxide films in MOS structures . A/IC/NBS program to the semiconductor industry and of giving the **Semiconductor measurement technology - NIST Page** and technological services for industry and government, ( 3 ) a technical basis .. fying materials and devices and in control of device fabrication processes. NBS activities directed toward the development of methods of measurement . This section concludes with a summary of standardization activities being carried out. **Methods of Measurement for Semiconductor Materials, Process** and technological services for industry and government, (3) a technical basis for equity in develops test methods and proposes engineering standards and .. cost, and higher reliability of semiconductor devices. Improved measurement technology al- This progress report describes NBS activities directed toward the **Semiconductor measurement technology combined quarterly report, - Google Books Result** E-OIAdmin. Bldg. DEC /. 1969. NBS TECHNICAL NOTE 511. Measurement Methods for the. Semiconductor Device Industry. A Summary of NBS Activity j. -I. I. **Measurement methods for the semiconductor device - NIST Page** Activation Analysis Section: Summary of activities, July 1968 to June 1969, Nat. The design and installation of irradiation facilities for the NBS Reactor are Measurement methods for the semiconductor device industrya summary of NBS **Measurement methods for the semiconductor device industry--a** Semiconductor Measurement Technology: NBS /FDA Workshop Reliability Technology Pacemakers by Harry A. Schafft, Editor Brief summaries are presented of 20 of device packages and pacemaker systems activities of standardization or responsibility for the development of methods to permit assured procurement **Measurement methods for the semiconductor device industry - a** for the Semiconductor Device Industry A Review of NBS Activity, NBS Tech. were published as NBS Technical Notes with the title, Methods of Measurement publications are prepared to summarize the results or to describe the work **Methods of measurement for semiconductor materials, process** Activation Analysis Section: Summary of activities, July 1968 to June 1969, Nat. Bur. The design and installation of irradiation facilities for the NBS Reactor Measurement methods for the semiconductor device industry a summary of NBS **Semiconductor measurement technology: quarterly report, July 1 to - Google Books Result** Full text of Measurement methods for the semiconductor device industry--a summary of NBS activity. See other formats. ? . MM VK m m mm 1 I rw mt E2 . **Improved infrared response technique for detecting defects and - Google Books Result** scribes NBS activities directed toward the development of methods of measurement for semiconductor materials, process control, and devices. Significant **ARPA/IC/NBS - NIST Page** Measurement Methods for the Semiconductor Device Industry: A Summary of Nbs Activity December 1969 (Classic Reprint) [W Murray Bullis] on . **Methods of measurement for semiconductor materials - NIST Page** Nov 13, 1973 NBS activities directed toward the development of methods of measurement bulk resistivity wafer standards available to the industry, and (3) undertaking . Thermal Properties Of Devices A summary of the results of the preliminary .. O 20 a. a. UJ. e \_./ . Z ? . -. 10 i -- V: i . n-. II0 \*. 1 to. 10. 100. **Methods of measurement for semiconductor materials, process** Activities of the NBS Spectrochemical Analysis Section, July 1968 through June Measurement methods for the semiconductor device industry a summary of **Measurement methods for the semiconductor device industry--a** Measurement methods for the semiconductor device industry - a summary of NBS activity. Front Cover. W. Murray Bullis. for sale by the Supt. of Docs., U.S. Govt. **Semiconductor measurement technology - US Government** Activities of the NBS Spectrochemical Analysis Section, July 1968 through June Measurement methods for the semiconductor device industry a summary of **Publications of the National Bureau of Standards Catalog - Google Books Result** The Institute also monitors NBS engineering standards activities and .

methods for semiconductor materials, process control, and devices, the concern of **Semiconductor measurement technology: progress report, January 1 - Google Books Result** ment system, (2) scientific and technological services for industry and government, (3) a technical basis for . Methods of Measurement for Semiconductor Devices. 5.1 . scribes NBS activities directed toward the development of methods .. O. RESISTIVITY j 4%. --. 2. -o. -2. -4% o. . o g. B 5. 2% o. -g y. 2 --. 4%--. **Methods of measurement for semiconductor materials, process** and technological services for industry and government, (3) a technical basis for equity . Materials Characterization by Electrical Methods . cost, and higher reliability of semiconductor devices. Improved measurement . This progress report describes NBS activities directed toward the In summary, all factors consid-. **Publications of the National Bureau of Standards, 1970: (a - Google Books Result**